



Description

JMT N And P-Channel Enhancement Mode MOSFET

Features

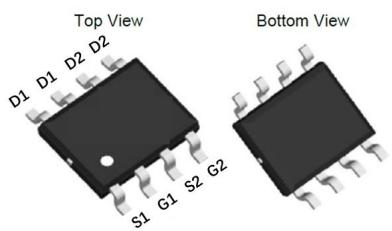
- N-Channel: 40V, 8A
 $R_{DS(ON)} < 22m\Omega @ V_{GS} = 10V$
 $R_{DS(ON)} < 35 m\Omega @ V_{GS} = 4.5V$
- P-Channel: -40V, -6A
 $R_{DS(ON)} < 53 m\Omega @ V_{GS} = -10V$
 $R_{DS(ON)} < 81m\Omega @ V_{GS} = -4.5V$
- Excellent Gate Charge x $R_{DS(ON)}$ Product(FOM)
- Very Low On-resistance $R_{DS(ON)}$
- Fast Switching Speed

Application

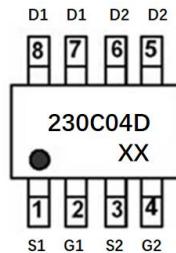
- Battery Protection
- Load Switch
- Power Management



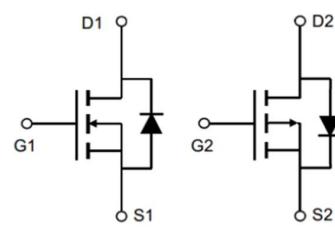
100% UIS TESTED!
100% ΔV_{ds} TESTED!



SOP-8



Marking and pin Assignment



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
230C04D	JMTP230C04D	TAPING	SOP-8	13inch	4000	48000

Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max. N-Channel	Max. P-Channel	Units
V_{DSS}	Drain-Source Voltage		40	-40	V
V_{GSS}	Gate-Source Voltage		± 20	± 20	V
I_D	Continuous Drain Current	$T_A = 25^\circ C$	8	-6	A
		$T_A = 100^\circ C$	5.2	-3.9	A
I_{DM}	Pulsed Drain Current ^{note1}		32	-24	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		13	17.6	mJ
P_D	Power Dissipation	$T_A = 25^\circ C$	2	3.2	W
$R_{Theta A}$	Thermal Resistance, Junction to Ambient		62.5	39	$^\circ C/W$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150		°C

**N-Channel Electrical Characteristics** ($T_J=25^\circ C$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=40V, V_{GS}=0V$	-	-	1.0	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	-	-	± 100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.5	2.5	V
$R_{DS(on)}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10V, I_D=8A$	-	17	22	$m\Omega$
		$V_{GS}=4.5V, I_D=5A$	-	25	35	$m\Omega$
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=20V, V_{GS}=0V, f=1.0MHz$	-	633	-	pF
C_{oss}	Output Capacitance		-	67	-	pF
C_{rss}	Reverse Transfer Capacitance		-	58	-	pF
Q_g	Total Gate Charge	$V_{DS}=20V, I_D=8A, V_{GS}=10V$	-	12	-	nC
Q_{gs}	Gate-Source Charge		-	3.2	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	3.1	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}= 20V, R_L = 2.5\Omega$ $V_{GS}=10V, R_{REN} = 3\Omega$	-	4	-	ns
t_r	Turn-on Rise Time		-	3	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	15	-	ns
t_f	Turn-off Fall Time		-	2	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current	-	-	8	A	
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	32	A	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0V, I_S= 8A$	-	-	1.2	V

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition : $T_J=25^\circ C, V_{DD}=20V, V_G=10V, L=0.5mH, Rg=25\Omega, I_{AS}=7.2A$ $T_J=25^\circ C, V_{DD}=-20V, V_G= -10V, L=0.5mH, Rg=25\Omega, I_{AS}=-8.4A$ 3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$

**P-Channel Electrical Characteristics** ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D = -250\mu\text{A}$	-40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -40\text{V}$, $V_{GS}=0\text{V}$	-	-	-1	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D = -250\mu\text{A}$	-1.0	-1.6	-2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS} = -10\text{V}$, $I_D = -6\text{A}$	-	41	53	$\text{m}\Omega$
		$V_{GS} = -4.5\text{V}$, $I_D = -4\text{A}$	-	58	81	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = -20\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$	-	860	-	pF
C_{oss}	Output Capacitance		-	87	-	pF
C_{rss}	Reverse Transfer Capacitance		-	70	-	pF
Q_g	Total Gate Charge	$V_{DS} = -20\text{V}$, $I_D = -6\text{A}$, $V_{GS} = -10\text{V}$	-	13	-	nC
Q_{gs}	Gate-Source Charge		-	3.8	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	3.1	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = -20\text{V}$, $R_L = 2.3\Omega$ $V_{GS} = -10\text{V}$, $R_{REN} = 6\Omega$	-	7.5	-	ns
t_r	Turn-on Rise Time		-	5.5	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	19	-	ns
t_f	Turn-off Fall Time		-	7	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain to Source Diode Forward Current	-	-	-6	A	
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-24	A	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_s = -6\text{A}$	-	-	-1.2	V

Typical Performance Characteristics-N

Figure1: Output Characteristics

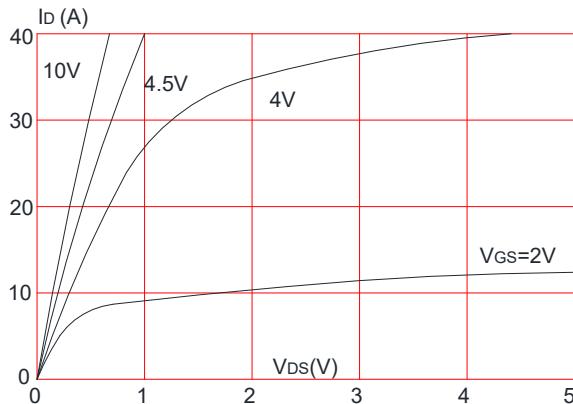


Figure 3: On-resistance vs. Drain Current

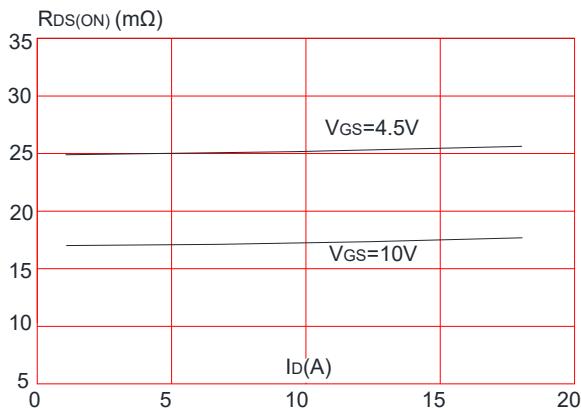


Figure 5: Gate Charge Characteristics

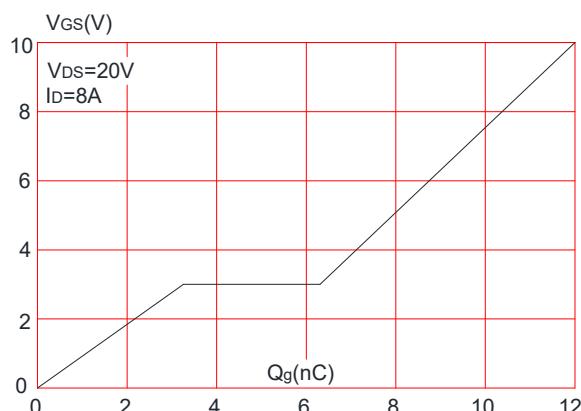


Figure 2: Typical Transfer Characteristics

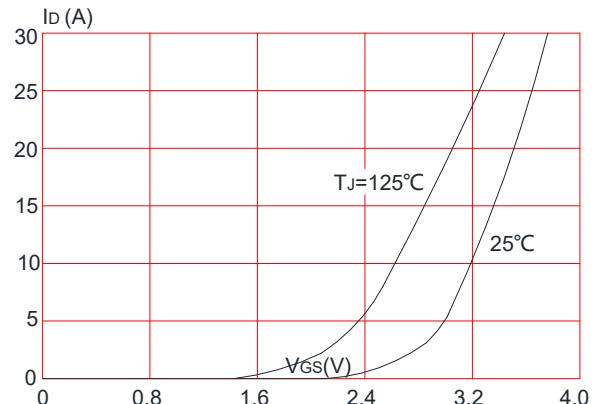


Figure 4: Body Diode Characteristics

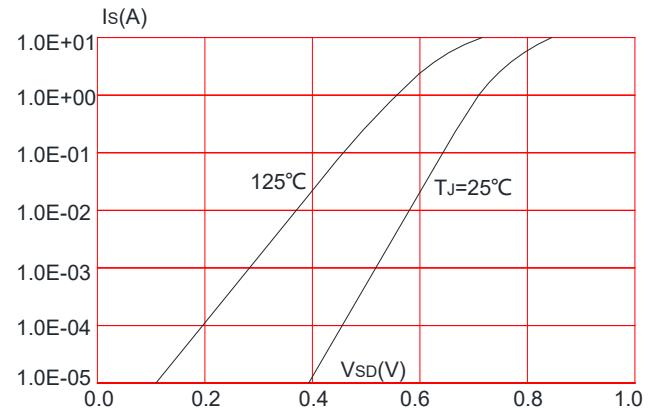


Figure 6: Capacitance Characteristics

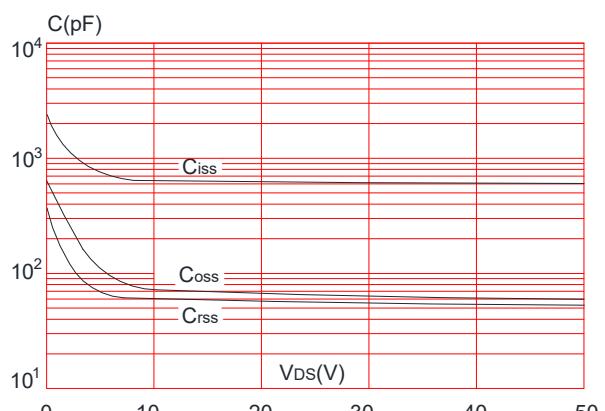


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

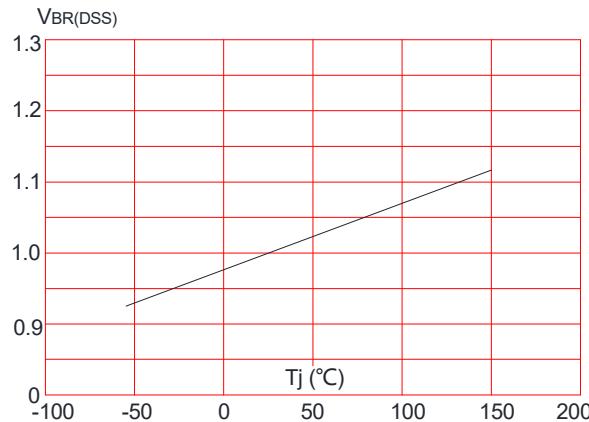


Figure 9: Maximum Safe Operating Area

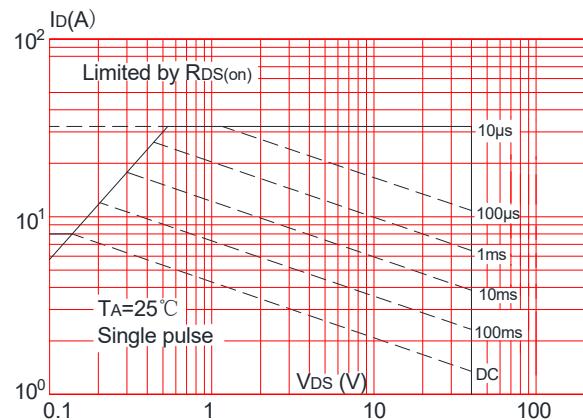


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

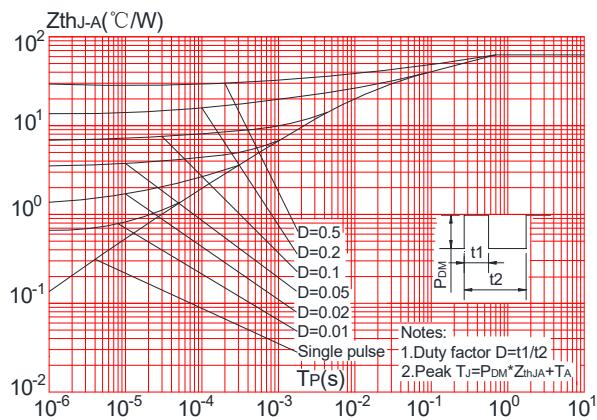


Figure 8: Normalized on Resistance vs. Junction Temperature

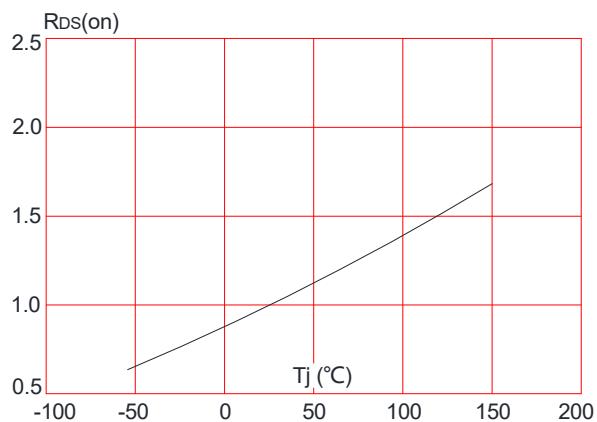
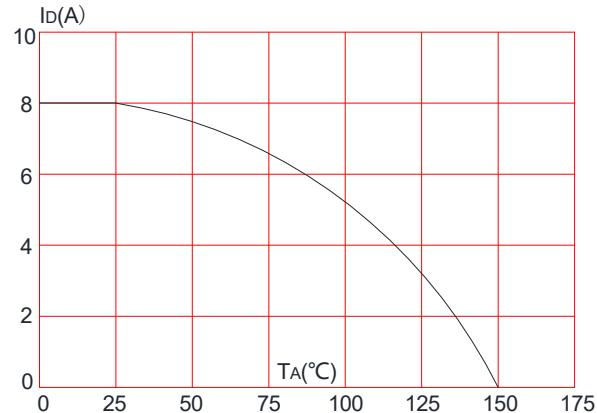


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature



Test Circuit-N

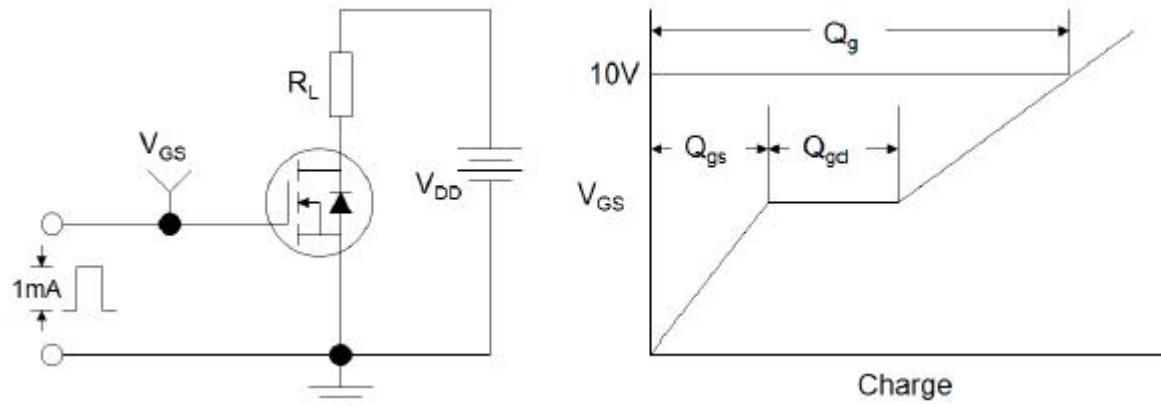


Figure1:Gate Charge Test Circuit & Waveform

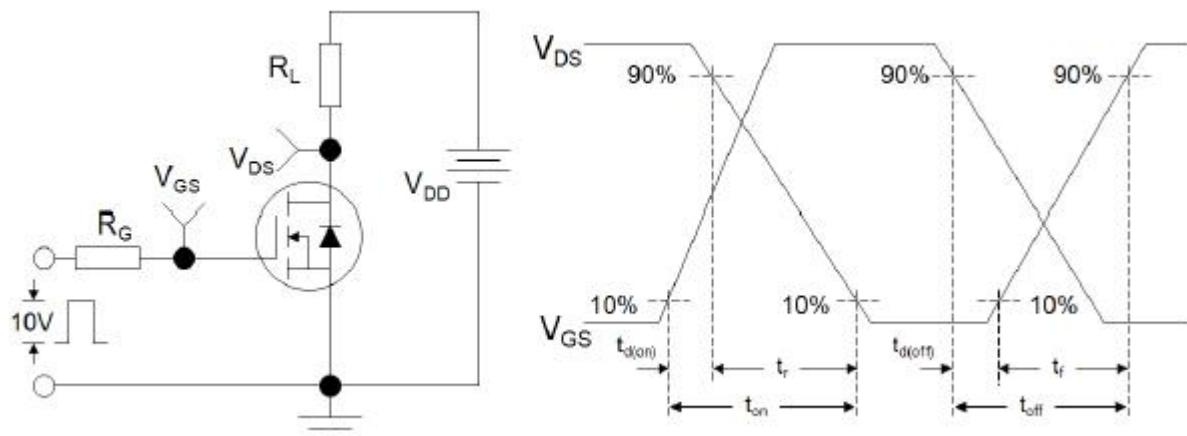


Figure 2: Resistive Switching Test Circuit & Waveforms

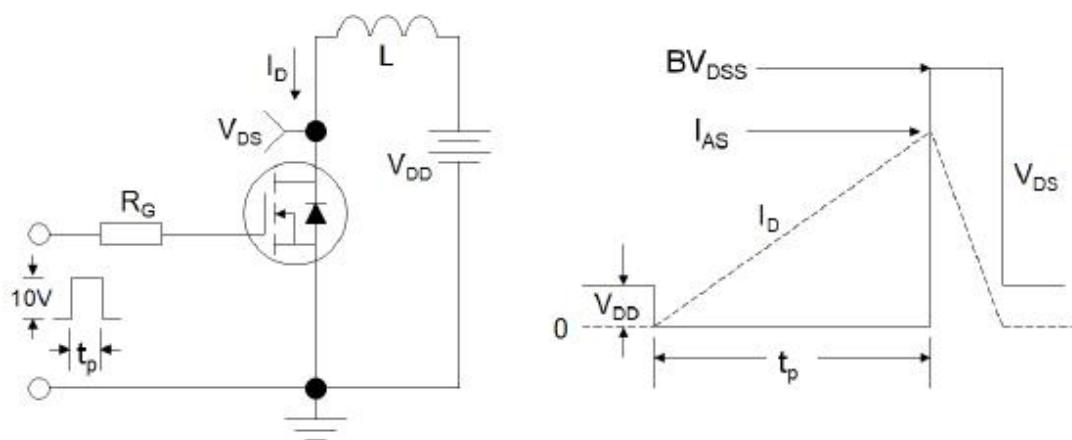


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

Typical Performance Characteristics-P

Figure1: Output Characteristics

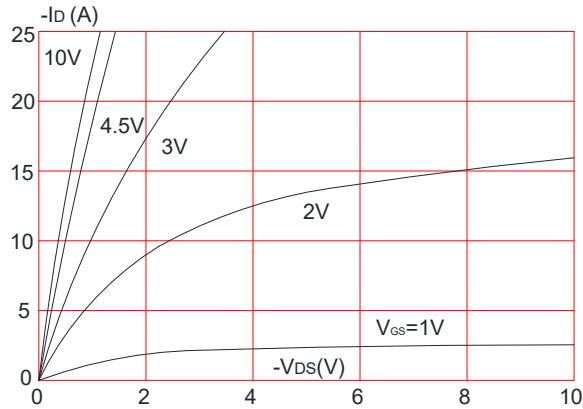


Figure 3: On-resistance vs. Drain Current

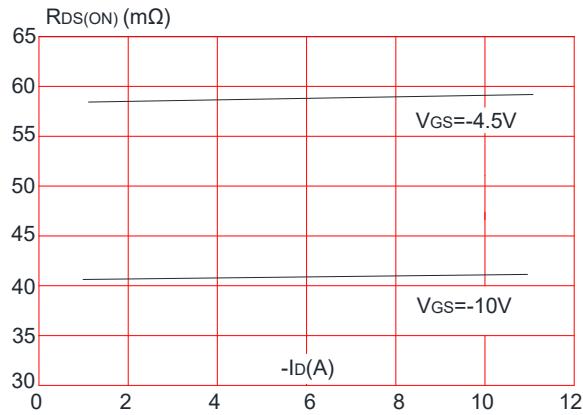


Figure 5: Gate Charge Characteristics

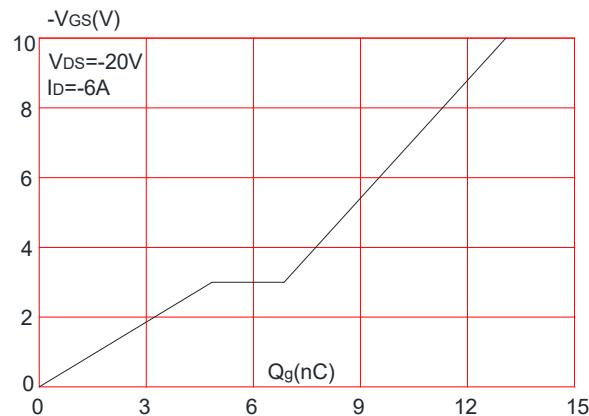


Figure 2: Typical Transfer Characteristics

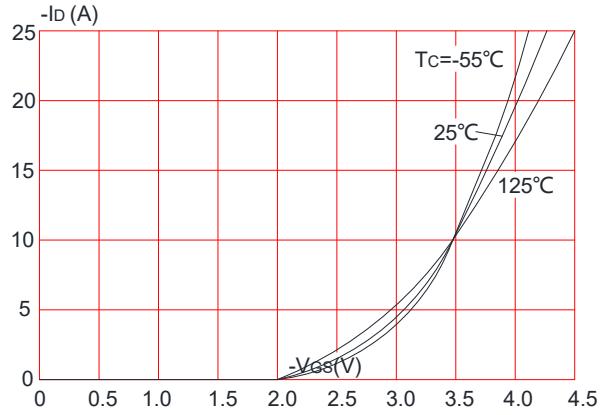


Figure 4: Body Diode Characteristics

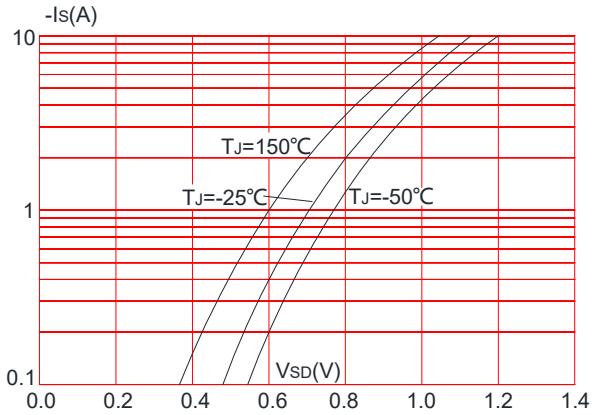


Figure 6: Capacitance Characteristics

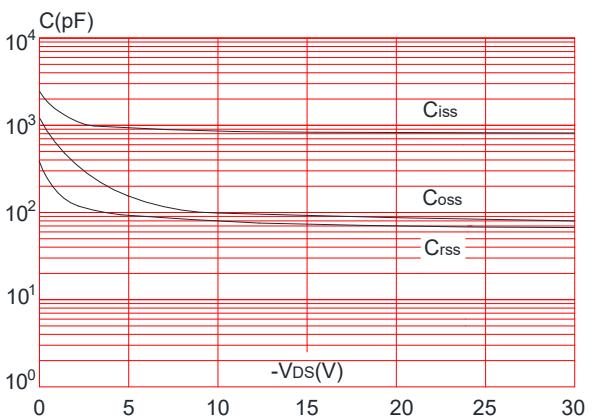


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

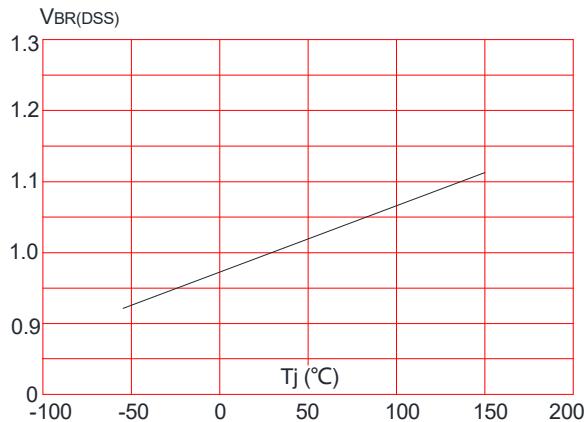


Figure 9: Maximum Safe Operating Area

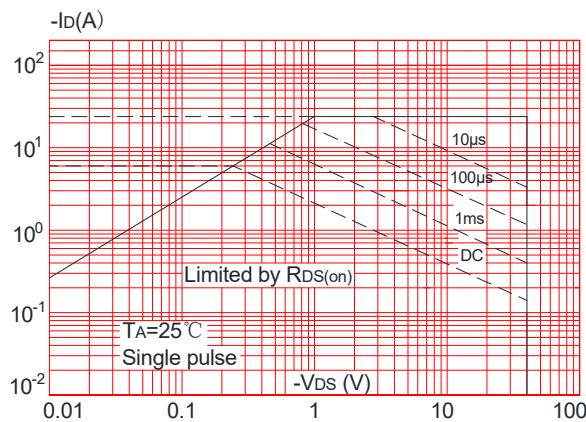


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

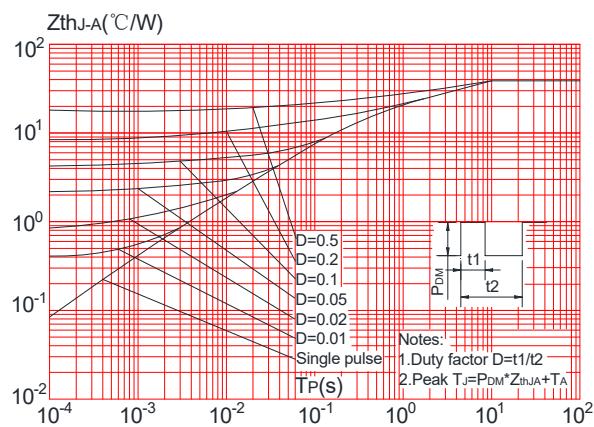


Figure 8: Normalized on Resistance vs. Junction Temperature

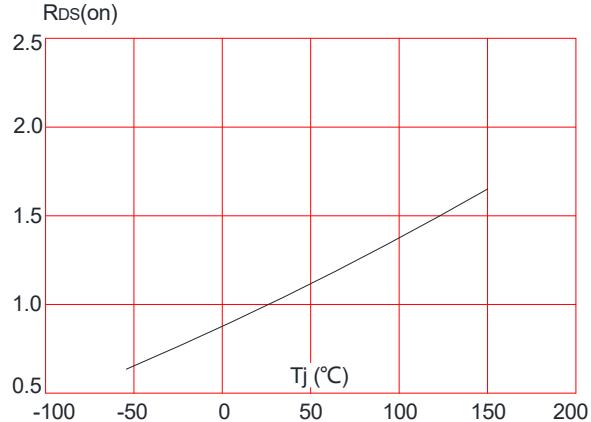
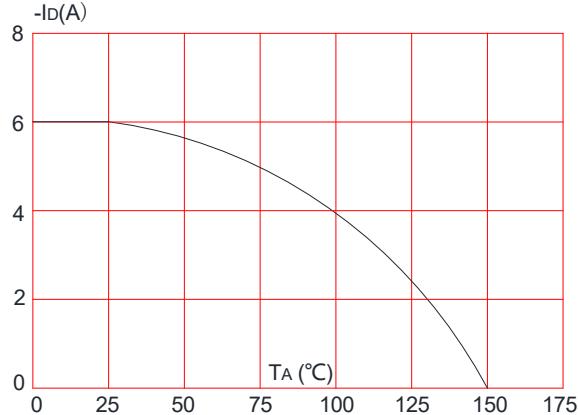
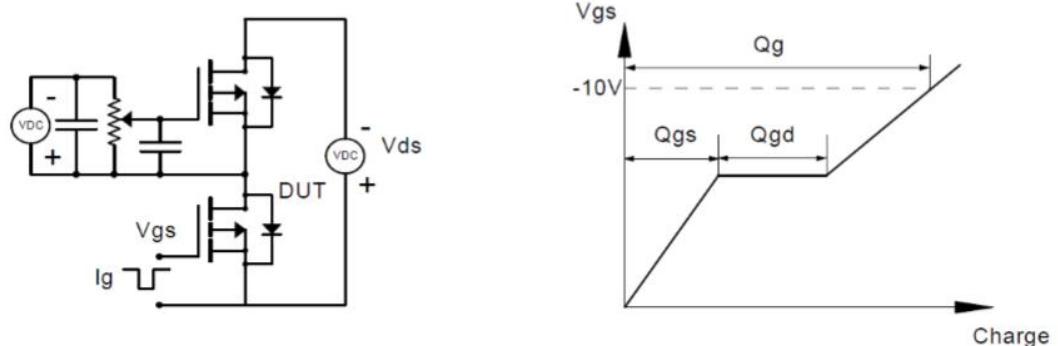


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

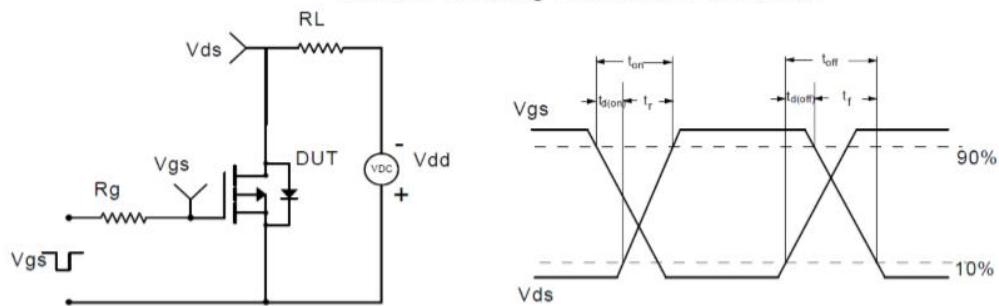


Test Circuit-P

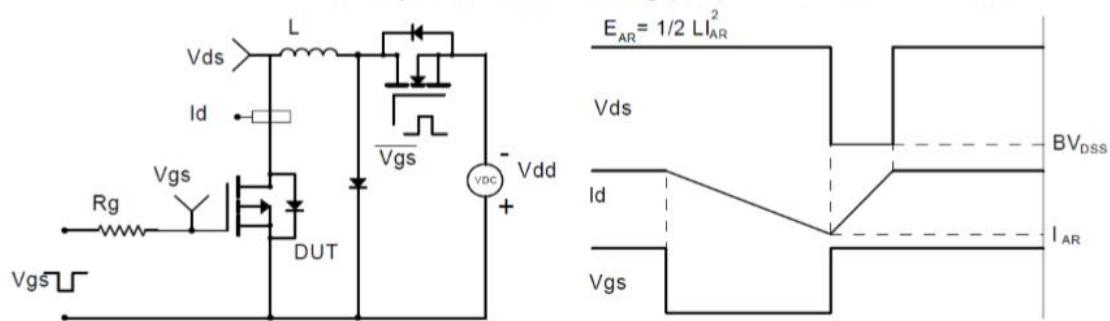
Gate Charge Test Circuit & Waveform



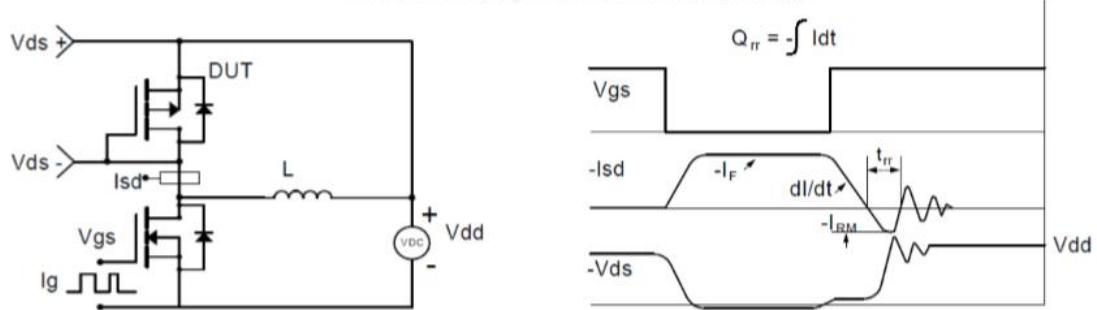
Resistive Switching Test Circuit & Waveforms



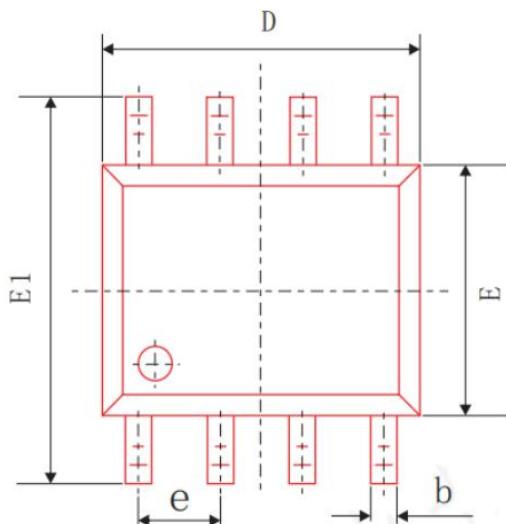
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



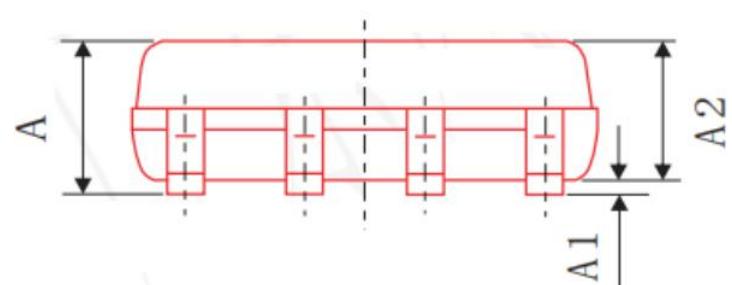
Diode Recovery Test Circuit & Waveforms



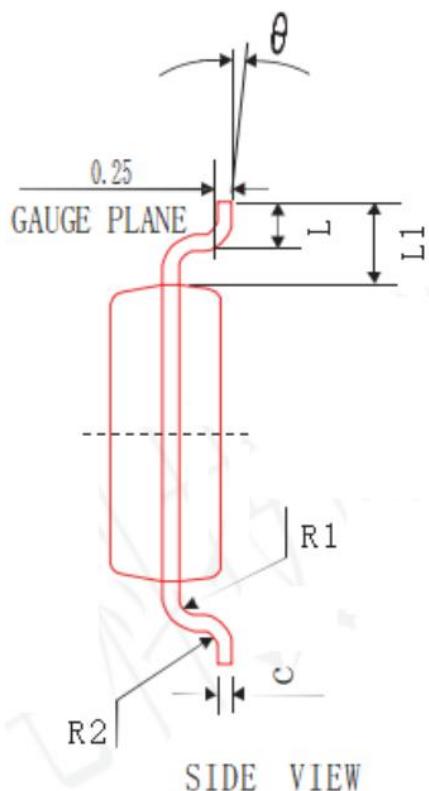
Package Mechanical Data-SOP-8



TOP VIEW



SIDE VIEW



SIDE VIEW

SYMBOL	MIN	NOM	MAX
A	1.40	1.60	1.80
A1	0.05	0.15	0.25
A2	1.35	1.45	1.55
b	0.30	0.40	0.50
c	0.153	0.203	0.253
D	4.80	4.90	5.00
E	3.80	3.90	4.00
E1	5.80	6.00	6.20
L	0.45	0.70	1.00
θ	2°	4°	6°
L1	1.04 REF		
e	1.27 BSC		
R1	0.07 TYP		
R2	0.07 TYP		



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